



4/17/2012

**RELIABILITY MONITOR REPORT
FOR**

MFN 250V Bipolar CMOS DMOS (BCD250)

MAXIM Integrated Products

120 San Gabriel Dr.
Sunnyvale, CA 94086

**This Report was prepared by
Maxim Reliability Engineering**

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX14803AEW	MAX14803CCM	MAX4802CQ1+	MAX5062AASA
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The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 17346 QUANTITY: 285 FAILS: 0 FITS: 6.6

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2011 and 3/31/2012 .

Process Information:

Process Description: MFN 250V Bipolar CMOS DMOS (BCD250)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1003	MAX14803CCM+	135C	120 HRS	80	0	NRSWD2006B
HIGH TEMP OP LIFE	1115	MAX4802CQ1+	135C	500 HRS	80	0	NEE1HA111G
HIGH TEMP OP LIFE	1124	MAX14803CCM+	135C	312 HRS	80	0	NRSWD2007BA
HIGH TEMP OP LIFE	N/A	MAX14803AEWZ+T	135C	558 HRS	45	0	NN1YAQ001A
Total:						0	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	1102	MAX5062AASA+	-65C TO 150C	1000 CYS	80	0	NOP0BA058DA
TEMP CYCLE, 5' RAMP, 10' DWELL	1102	MAX14803CCM+	-65C TO 150C	1000 CYS	80	0	NRSWDU022C
TEMP CYCLE, 5' RAMP, 10' DWELL	1115	MAX4802CQ1+	-65C TO 150C	1000 CYS	80	0	NEE1HA111G
Total:						0	

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